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3.3 V FULL-DUPLEX RS-485/RS-422 DRIVERS AND BALANCED RECEIVERS

FEATURES

- Designed for INTERBUS Applications
- Designed for RS-422 and RS-485 Networks
- Balanced Receiver Thresholds
- 1/2 Unit-Load (up to 64 nodes on the bus)
- Bus-Pin ESD Protection 15 kV HBM
- Bus-Fault Protection of –7 V to 12 V
- Thermal Shutdown Protection
- Power-Up/Down Glitch-free Bus Inputs and Outputs
- High Input Impedance With Low V_{CC}
- Monotonic Outputs During Power Cycling
- 5-V Tolerant Inputs

APPLICATIONS

- Digital Motor Control
- Utility Meters
- Chassis-to-Chassis Interconnections
- Electronic Security Stations
- Industrial, Process, and Building Automation
- Point-of-Sale (POS) Terminals and Networks
- DTE/DCE Interfaces

DESCRIPTION

The SN65HVD379 is a differential line driver and differential-input line receiver that operates with a 3.3-V power supply. Each driver and receiver has separate input and output pins for full-duplex bus communication designs. They are designed for balanced transmission lines and interoperation with ANSI TIA/EIA-485A, TIA/EIA-422-B, ITU-T v.11, and ISO 8482:1993 standard-compliant devices.

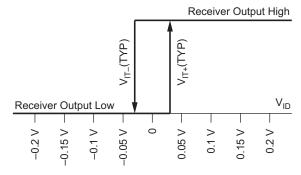
These differential bus drivers and receivers are monolithic, integrated circuits designed for full-duplex bi-directional data communication on multipoint bus-transmission lines at signaling rates⁽¹⁾ up to 25 Mbps. The SN65HVD379 is fully enabled with no external enabling pins.

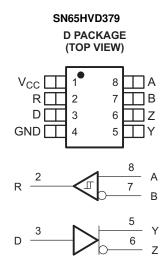
The 1/2 unit load receiver has a higher receiver input resistance. This results in lower bus leakage currents over the common-mode voltage range, and reduces the total amount of current that an RS-485 driver is forced to source or sink when transmitting.

The balanced differential receiver input threshold makes the SN65HVD379 more compatible with fieldbus requirements that define an external failsafe structure.

 The signaling rate of a line is the number of voltage transitions that are made per second expressed in the units bps (bits per second).

BALANCED RECEIVER INPUT THRESHOLDS







Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.





This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

ORDERING INFORMATION

SIGNALING RATE	UNIT LOADS	PART NUMBER ⁽¹⁾	SOIC MARKING
25 Mbps	1/2	SN65HVD379	

(1) These are The D package is available taped and reeled. Add an R suffix to the part number (ie. SN65HVD379DR).

ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range unless otherwise noted(1) (2)

		UNIT
V _{CC}	Supply voltage range	-0.3 V to 6 V
V_A , V_B , V_Y , V_Z	Voltage range at any bus terminal (A, B, Y, Z)	–9 V to 14 V
V _{TRANS}	Voltage input, transient pulse through 100 Ω. See Figure 8 (A, B, Y, Z) ⁽³⁾	-50 to 50 V
V _I	Input voltage range (D, DE, RE)	-0.5 V to 7 V
P _{CONT}	Continuous total power dissipation	Internally limited (4)
Io	Output current (receiver output only, R)	11 mA

⁽¹⁾ Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under recommended operating conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- (2) All voltage values, except differential I/O bus voltages, are with respect to network ground terminal.
- (3) This tests survivability only and the output state of the receiver is not specified.
- (4) The Thermal shutdown protection circuit internally limits the continuous total power dissipation. Thermal shutdown typically occurs when the junction temperature reaches 165C.

RECOMMENDED OPERATING CONDITIONS

over operating free-air temperature range unless otherwise noted

PARAMET	ΓER		MIN	NOM	MAX	UNIT
V _{CC}	Supply voltage	supply voltage				V
V_{I} or V_{IC}	Voltage at any bus termina	I (separately or common mode)	-7 ⁽¹⁾		12	V
1/t _{UI}	Signaling rate	SN65HVD379			25	Mbps
R _L	Differential load resistance		54	60		Ω
V_{IH}	High-level input voltage	D	2		V_{CC}	ı
V_{IL}	Low-level input voltage	D	0		0.8	V
V_{ID}	Differential input voltage		-12		12	İ
	High lovel output ourrent	Driver	-60			mA
I _{OH} High-level output current		Receiver	-8			IIIA
I _{OL} Low-level output current		Driver			60	mA
		Receiver			8	IIIA
T _A	Ambient still-air temperatur	e	-40		85	С

(1) The algebraic convention, in which the least positive (most negative) limit is designated as minimum is used in this data sheet.

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ELECTROSTATIC DISCHARGE PROTECTION

PARAMETER	TEST CONDITIONS	MIN TYP ⁽¹⁾ MAX	UNIT
Human body model	Bus terminals and GND	16	
Human body model ⁽²⁾	All pins	4	kV
Charged-device-model ⁽³⁾	All pins	1	

- All typical values at 25C with 3.3-V supply. Tested in accordance with JEDEC Standard 22, Test Method A114-A.
- Tested in accordance with JEDEC Standard 22, Test Method C101.

DRIVER ELECTRICAL CHARACTERISTICS

over recommended operating conditions unless otherwise noted

	PARAMET	ER	TEST CONE	DITIONS	MIN	TYP ⁽¹⁾	MAX	UNIT
V _{I(K)}	Input clamp voltage		I _I = -18 mA		-1.5			
			I _O = 0		2		V _{CC}	
177	Ctoody atota different	ial autout valtaga	$R_L = 54 \Omega$, See Figure	1 ⁽²⁾ (RS-485)	1.5	2.0		
V _{OD(SS)}	Steady-state different	iai output voitage	$R_L = 100 \Omega$, See Figur	e 1 (RS-422)	2	2.3		
			$V_{\text{test}} = -7 \text{ V to } 12 \text{ V, Se}$	ee Figure 2	1.5			
$\Delta V_{OD(SS)} $	Change in magnitude differential output volt		$R_L = 54 \Omega$, See Figure	1 and Figure 2	-0.2		0.2	V
V _{OD(RING)}	Differential output vol undershoot	tage overshoot and	$R_L = 54 \Omega$, $C_L = 50 pF$ (Figure 3 for definitions				10% ⁽³⁾	
V _{OC(PP)}	Peak-to-peak commo	n-mode output voltage				0.5		
V _{OC(SS)}	Steady-state commor	n-mode output voltage	See Figure 3		1.6		2.3	
$\Delta V_{OC(SS)}$	Change in steady-sta voltage	te common-mode output			-0.05		0.05	
	High impedance state	a cutaut current	$V_{CC} = 0 \text{ V}, V_{Z} \text{ or } V_{Y} = 0$ Other input at 0 V	12 V,			90	0
$I_{Z(Z)}$ or $I_{Y(Z)}$ High-impedance state output current		e output current	$V_{CC} = 0 \text{ V}, V_{Z} \text{ or } V_{Y} = 0$ Other input at 0 V	–7 V,	-10			μΑ
I _{Z(S)} or Short-circuit output current ⁽⁴⁾		V_Z or $V_Y = -7 \text{ V}$	Other input	-250		250	A	
$I_{Y(S)}$	Short-circuit output cu	urrent' '/	V_Z or $V_Y = 12 V$	at 0 V	-250		250	mA
I _I	Input current D		$V_{I} = 0 \text{ or } V_{I} = 2.0$		0		100	Α
C _(OD)	Differential output cap	pacitance	$V_{OD} = 0.4 \sin (4E6\pi t) - V_{CC} \text{ at } 0 \text{ V}$	+ 0.5 V,		16		pF

- All typical values are at 25C and with a 3.3-V supply.
- V_{CC} is 3.3 Vdc 5%
- 10% of the peak-to-peak differential-output voltage swing, per TIA/EIA-485.
- Under some conditions of short-circuit to negative voltages, output currents exceeding the ANSI TIA/EIA-485-A maximum current of 250 mA may occur. Continuous exposure may affect device reliability.

DRIVER SWITCHING CHARACTERISTICS

over recommended operating conditions unless otherwise noted

	PARAMETER	TEST CONDITIONS	MIN	TYP ⁽¹⁾	MAX	UNIT
t _{PLH}	Propagation delay time, low-to-high-level output		4	10	18	
t _{PHL} Propagation delay time, high-to-low-level output			4	10	10	ns
t _r	Differential output signal rise time	$R_L = 54 \Omega$, $C_L = 50 pF$, See Figure 5	0.5	-	12	20
t _f Differential output signal fall time			2.5	5	12	ns
t _{sk(p)} Pulse skew (t _{PHL} - t _{PLH})				0.6		ns
t _{sk(pp)} (2)	Part-to-part skew			1		ns

(1) All typical values are at 25C and with a 3.3-V supply.

 $t_{sk(pp)}$ is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices operate with the same supply voltages, at the same temperature, and have identical packages and test circuits.

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RECEIVER ELECTRICAL CHARACTERISTICS

over recommended operating conditions unless otherwise noted

	PARAMETER	TEST CONDITIO	NS	MIN	TYP ⁽¹⁾	MAX	UNIT
$V_{\text{IT+}}$	Positive-going differential input threshold voltage	$I_O = -8 \text{ mA}$				0.2	
V _{IT-}	Negative-going differential input threshold voltage	I _O = 8 mA		-0.2			V
V_{hys}	Hysteresis voltage (V _{IT+} - V _{IT-})				50		mV
Vo	Output voltage	$V_{ID} = 200 \text{ mV}, I_{O} = -8 \text{ mA}, Se$	ee Figure 7	2.4			V
v _O	Output voltage	$V_{ID} = -200 \text{ mV}, I_O = 8 \text{ mA}, \text{ See Figure 7}$				0.4	V
		V_A or $V_B = 12 V$			0.20	0.35	
I _A or	Bus input current	V_A or $V_B = 12 V$, $V_{CC} = 0 V$	Other input		0.24	0.40	mA
I _B	bus input current	V_A or $V_B = -7 V$	at 0 V	-0.35	-0.18		IIIA
		V_A or $V_B = -7 V$, $V_{CC} = 0 V$		-0.25	-0.13		
C _{ID}	Differential input capacitance	$V_{ID} = 0.4 \sin (4E6\pi t) + 0.5 V,$	DE at 0 V		15		pF
I _{CC}	Supply current	D at 0 V or V _{CC} and No Load				2.1	mA

⁽¹⁾ All typical values are at 25C and with a 3.3-V supply.

RECEIVER SWITCHING CHARACTERISTICS

over recommended operating conditions unless otherwise noted

	PARAMETER	TEST CONDITIONS	MIN	TYP ⁽¹⁾	MAX	UNIT
t _{PLH}	Propagation delay time, low-to-high-level output	$V_{ID} = -1.5 \text{ V to } 1.5 \text{ V}, C_L = 15 \text{ pF},$		26	45	20
t _{PHL}	Propagation delay time, high-to-low-level output	See Figure 7		20	45	ns
t _{sk(p)}	Pulse skew (t _{PHL} - t _{PLH})				7	
t _{sk(pp)}	Part-to-part skew ⁽²⁾			5		
t _r	Output signal rise time				5	
t _f	Output signal fall time				6	

DEVICE POWER DISSIPATION - PD

	PARAMETER	TEST CONDITIONS	MIN	TYP MAX	UNIT
P_{D}	Device power dissipation	$R_L = 60$, $C_L = 50$ pF, Input to D a 50% duty cycle square wave at indicated signaling rate $T_A = 85C$		197	mW

FUNCTION TABLES

	DRIVER		RECEIVER	
INPUT	ТИО	PUTS	DIFFERENTIAL INPUTS	OUTPUTS
D	Y Z		$V_{ID} = V_A - V_B$	R
Н	Н	L	V _{ID} ≤ -0.2 V	L
L	L	Н	−0.2 V < V _{ID} < 0.2 V	?
Open	L	Н	0.2 V ≤ V _{ID}	Н

All typical values are at 25C and with a 3.3-V supply $t_{sk(pp)}$ is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices operate with the same supply voltages, at the same temperature, and have identical packages and test circuits.



PARAMETER MEASUREMENT INFORMATION

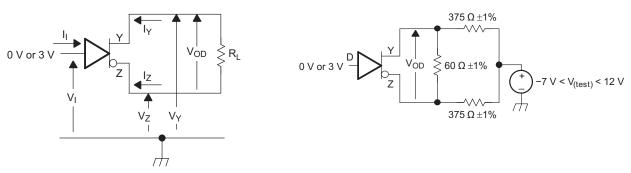


Figure 1. Driver V_{OD} Test Circuit and Voltage and Current Definitions

Figure 2. Driver V_{OD} With Common-Mode Loading Test Circuit

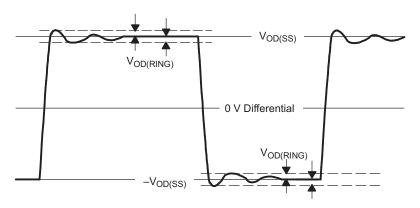


Figure 3. $V_{\text{OD(RING)}}$ Waveform and Definitions

 $V_{\text{OD(RING)}}$ is measured at four points on the output waveform, corresponding to overshoot and undershoot from the $V_{\text{OD(H)}}$ and $V_{\text{OD(L)}}$ steady state values.

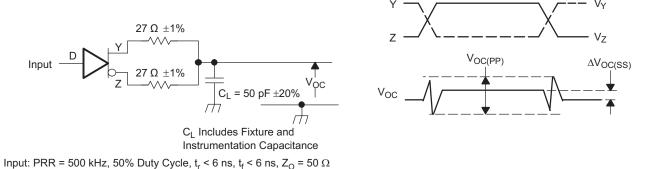
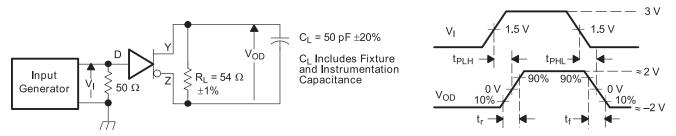


Figure 4. Test Circuit and Definitions for the Driver Common-Mode Output Voltage

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PARAMETER MEASUREMENT INFORMATION (continued)



Generator: PRR = 500 kHz, 50% Duty Cycle, $t_{\rm r}$ < 6 ns, $t_{\rm f}$ < 6 ns, $Z_{\rm O}$ = 50 Ω

Figure 5. Driver Switching Test Circuit and Voltage Waveforms

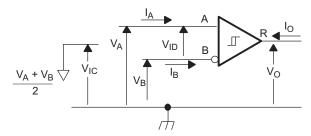


Figure 6. Receiver Voltage and Current Definitions

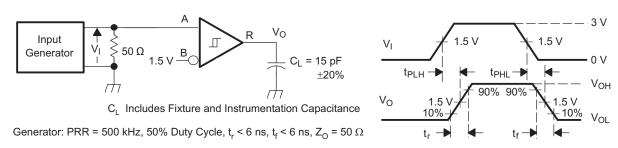


Figure 7. Receiver Switching Test Circuit and Voltage Waveforms

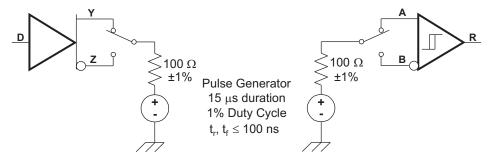
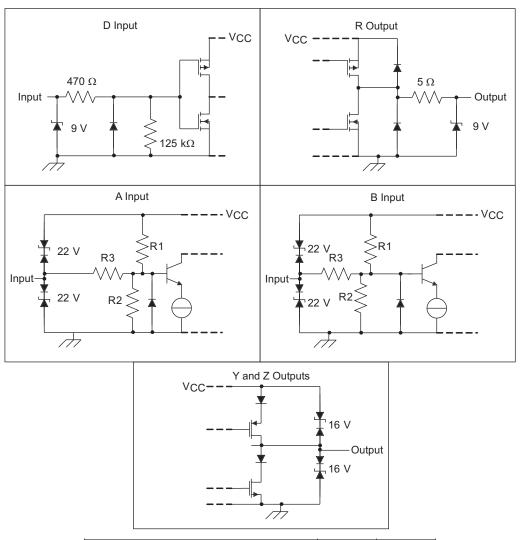


Figure 8. Test Circuit, Transient Over Voltage Test



EQUIVALENT INPUT AND OUTPUT SCHEMATIC DIAGRAMS





TYPICAL CHARACTERISTICS

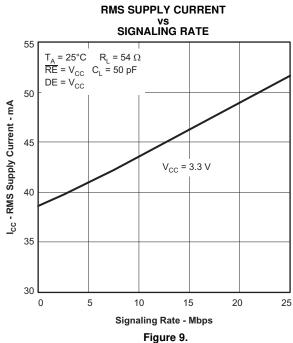
250

200

150

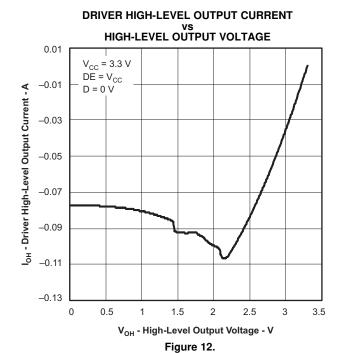
 $T_A = 25$ °C $\overline{RE} = 0 \text{ V}$

DE = 0 V



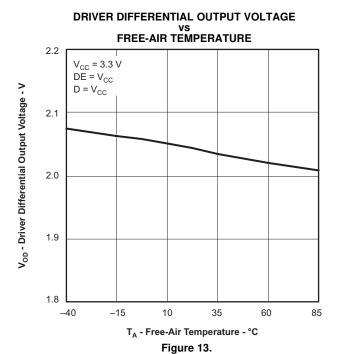
BUS INPUT CURRENT VS BUS INPUT VOLTAGE

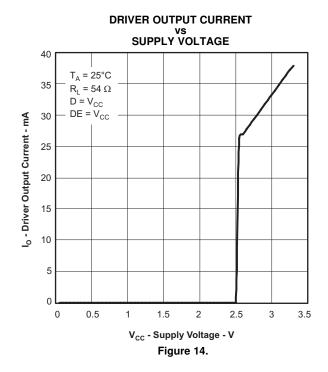
DRIVER LOW-LEVEL OUTPUT CURRENT vs LOW-LEVEL OUTPUT VOLTAGE 0.14 V_{CC} = 3.3 V DE = V_{CC} 0.12 IoL - Driver Low-Level Output Current - A D = 0 V0.1 0.08 0.06 0.04 0.02 0 -0.020 1.5 2 V_{OL} - Low-Level Output Voltage - V Figure 11.





TYPICAL CHARACTERISTICS (continued)





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PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
SN65HVD379D	NRND	SOIC	D	8	75	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	VP379	
SN65HVD379DG4	NRND	SOIC	D	8	75	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	VP379	
SN65HVD379DR	ACTIVE	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	VP379	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- ⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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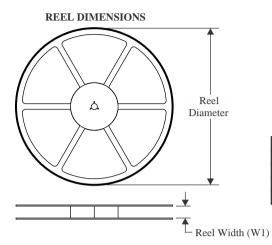
PACKAGE OPTION ADDENDUM

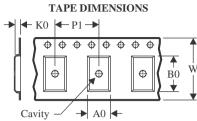
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PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

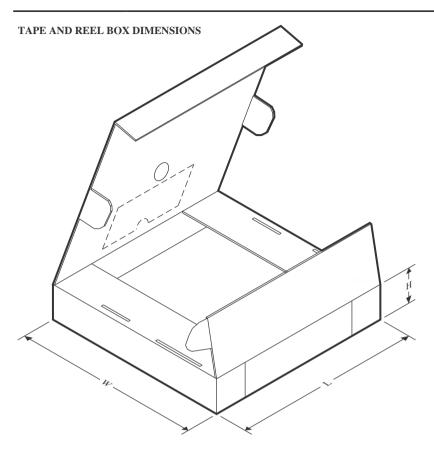


*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN65HVD379DR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1

PACKAGE MATERIALS INFORMATION

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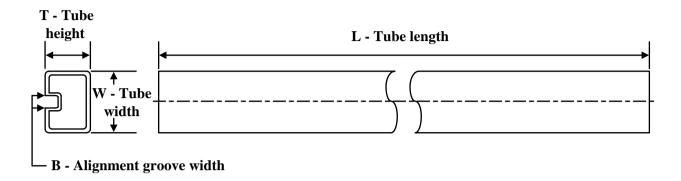
*All dimensions are nominal

Device Pack		Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN65HVD379D	R	SOIC	D	8	2500	356.0	356.0	35.0

PACKAGE MATERIALS INFORMATION

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TUBE



*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
SN65HVD379D	D	SOIC	8	75	506.6	8	3940	4.32
SN65HVD379DG4	D	SOIC	8	75	506.6	8	3940	4.32

PACKAGE OUTLINE

SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



NOTES:

- 1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 [0.15] per side.
- 4. This dimension does not include interlead flash.5. Reference JEDEC registration MS-012, variation AA.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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